

Opto-Electronics Review, 2015, volume 23, issue 2, pp. 149-164

Review of night vision metrology

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DOI: <https://doi.org/10.1515/oere-2015-0024>

Abstract:

A review of night vision metrology is presented in this paper. A set of reasons that create a rather chaotic metrologic situation on night vision market is presented. It is shown that there has been made a little progress in night vision metrology during last decades in spite of a big progress in night vision technology at the same period of time. It is concluded that such a big discrepancy between metrology development level and technology development can be an obstacle in the further development of night vision technology.